

Notice of References Cited	Application/Control No. 10/657,989	Applicant(s)/Patent Under Reexamination DANDEKAR ET AL.	
	Examiner Qing Chen	Art Unit 2191	Page 1 of 2

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,991,543	11-1999	Amberg et al.	717/175
*	B	US-6,075,943	06-2000	Feinman, Mark S.	717/175
*	C	US-6,080,207	06-2000	Kroening et al.	717/172
*	D	US-6,088,803	07-2000	Tso et al.	726/22
*	E	US-6,131,192	10-2000	Henry, Craig James	717/175
*	F	US-6,378,054 B1	04-2002	Karasudani et al.	711/161
*	G	US-6,385,766 B1	05-2002	Doran et al.	717/174
*	H	US-6,543,047 B1	04-2003	Vrhel et al.	717/121
*	I	US-6,549,914 B1	04-2003	Valys, David T.	707/104.1
*	J	US-6,550,062 B2	04-2003	Barajas et al.	717/178
*	K	US-6,591,418 B2	07-2003	Bryan et al.	717/177
*	L	US-6,598,223 B1	07-2003	Vrhel et al.	717/174
*	M	US-6,718,373 B1	04-2004	Bearden et al.	709/220

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

Notice of References Cited	Application/Control No. 10/657,989		Applicant(s)/Patent Under Reexamination DANDEKAR ET AL.	
	Examiner Qing Chen		Art Unit 2191	Page 2 of 2

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,721,946 B1	04-2004	Fogarty et al.	717/175
*	B	US-6,938,250 B2	08-2005	Cohen et al.	717/178
*	C	US-2002/0087965 A1	07-2002	Lin, Jiann-Shiun	717/174
*	D	US-2002/0112232 A1	08-2002	Ream et al.	717/176
*	E	US-2002/0156877 A1	10-2002	Lu et al.	709/221
*	F	US-2002/0188942 A1	12-2002	BRYAN et al.	717/176
*	G	US-2003/0028629 A1	02-2003	Amro et al.	709/222
*	H	US-2003/0192043 A1	10-2003	Lin et al.	717/178
*	I	US-2004/0025155 A1	02-2004	Sedlack et al.	717/174
*	J	US-2005/0055688 A1	03-2005	Barajas et al.	717/174
*	K	US-2005/0172284 A1	08-2005	Dandekar et al.	717/175
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.